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ABBREVIATIONS AND SYMBOLS



	K_{lpha}	radiation of K series
	k _{ij}	electromecharnical coupling
	LCR	Inductance/Capacitance/Resistance
	MW	molecular weight
	МРВ	Morphotropic Phase Boundaries
	МСР	Mixed and Calcination Processes
	Р-Е	polarization versus electric field
c	Ps	spontaneous polarization
	Pr	remanent polarization
	Р	paraelectric
	PVA	poly(vinyl alcohol)
	ri	radius of atom
	R	relaxor ferroelectric
	Rh. Domain	rhombohedral domains
	SEM	scanning electron microscopy
	S _{ij}	field-induced strain
S a	TEM	transmission electron microscopy
QU	To	Curie-Weiss temperature
Cop	Trright	Rhombohedral to Tetragonal temperature
AI	T _{max}	temperature at maximum permittivity
	T _m	Transition temperature
	T _c	Curie point
	Tet. Domain	tetragonal domains

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t thickness; tolerance factor $tan \delta$ loss tangent voltage; volume 2157 V XRD x-ray diffraction electronegativity differences of cation A and oxygen X_{A-O} electronegativity differences of cation B and oxygen X_{B-C} diffuseness parameter δ real part of the permittivity permittivity of free space relative permittivity the permittivity at T_{max} ε_{max} critical exponent γ driving frequency ω

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